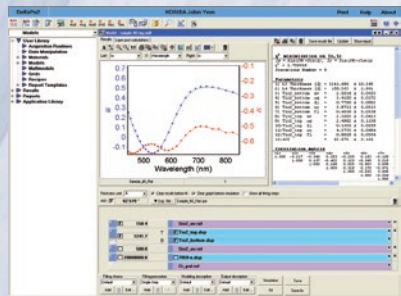




## DeltaPsi2 Scientific Mode to Extend the Measurement Capability



DeltaPsi2 is a fully integrated spectroscopic ellipsometry platform that includes advanced measurement and analysis capabilities and a complete materials database.

This software is ideal for engineering applications for new sample characterization or optimization of an existing experimental recipe. Once the new recipe is validated it can be performed repeatedly without expert intervention.



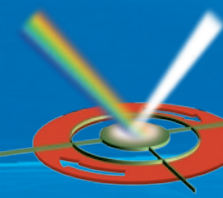
## Auto Soft

"User Oriented  
Software Platform"

Fully Automatic Mode  
for Routine Analysis

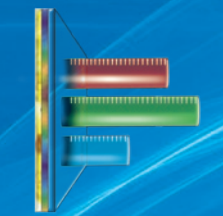
### 1> Load Sample

- Automatic adjustment of the sample
- Visualization of the spot on the sample with the MyAutoView vision system
- Choose your measurement site



### 2> Run Measurement

- Select your experimental recipe in the ready to use application database
- Push the Run button
- Measure at a single position or multiple positions to map thin film uniformity



### 3> Accurate Results

- Clear table provides thickness, optical constants, film uniformity and other material properties of the sample
- Thin film result status: in or out tolerance limits
- Automatic reporting
- Reprocessing capability



## Worldwide Customer Support

Founded nearly 190 years ago, HORIBA Jobin Yvon is one of world's largest manufacturers of analytical and spectroscopic systems and components. Our instruments are manufactured under a strict quality assurance program and are supported by a worldwide network of strategically located facilities in the United States, Europe and Asia that are ready to provide assistance when and where it is needed. Our staff of highly trained service and application specialists install and certify instrument performance, and conduct technical and application user training for smooth and efficient commissioning of the instruments. This commitment to product excellence and continued support is part of the HORIBA Jobin Yvon culture.

Find us at [www.jobinyvon.com](http://www.jobinyvon.com) or contact us:

**France :** HORIBA Jobin Yvon S.A.S., Z.I. La Vigne aux Loups, 5 avenue Arago, 91380 Chilly-Mazarin  
Tel: +33 (0)1 64 54 13 00 - Fax: +33 (0)1 69 74 88 61 - Email: [tf-sales@jobinyvon.fr](mailto:tf-sales@jobinyvon.fr) - [www.jobinyvon.fr](http://www.jobinyvon.fr)  
**USA :** HORIBA Jobin Yvon Inc., 3880 Park Avenue, Edison, NJ 08820-3012. Toll-free: +1-866-jobinyvon  
Tel: +1 732 494 8660 - Fax: +1 732 549 5125 - Email: [info@jobinyvon.com](mailto:info@jobinyvon.com) - [www.jobinyvon.com](http://www.jobinyvon.com)  
**Japan :** HORIBA Ltd., JY Optical Sales Dept., Higashi-Kanda, Daiji Building, 1-7-8 Higashi-Kanda Chiyoda-ku,  
Tokyo 101-0031 - Tel: +81 (0)3 3861 8231 - Fax: +81 (0)3 3861 8259 - Email: [info@horiba.co.jp](mailto:info@horiba.co.jp)  
**Germany :** +49 (0)89 46 23 170 **Italy:** +39 02 57 60 30 50 **UK:** +44 (0)20 8204 8142  
**China :** +86 (0)10 8567 9966 **Other countries:** +33 (0)1 64 54 13 00 **Korea:** +82 (0)2 753 7911

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[www.autose.org](http://www.autose.org)

Explore the future

## Auto SE Specifications

### Standard Configuration

Light source	Combination halogen and blue LED
Spectral range	440 – 850 nm
Spot size	> 500 µm; 500 µm x 500 µm; 250 µm x 500 µm; 250 µm x 250 µm; 70 µm x 250 µm; 100 µm x 100 µm; 50 µm x 60 µm; 25 µm x 60 µm
Detector	CCD – Resolution: 2 nm
Sample stage	200 mm x 200 mm, automatic XYZ adjustment, vacuum check, Z height 50 mm
Sample viewing	CCD camera – Field of view: 1.33*1 mm Resolution: 10 µm
Goniometer	Fixed at 70° - Possible set up at 66° or 61.5°

### Options

Accessories	• Sample cells: Temperature controlled cell, Electrochemical cell, Liquid cell • Sample stage: Autosampler, 360° Rotation control, Transmission mount, Plastic film mounts, Lens and curved sample mounts Xenon lamp needed for spot sizes < 100 x 100 µm Dimension (wxdxh): 1400-1840 x 530 x 740 mm
Microspot Table	

### Performance

Measurement time	< 1 s, typical 5 s
Accuracy	NIST 1000 Å SiO <sub>2</sub> /Si: d ± 4 Å - n(632.8 nm) ± 0.002 Fused silica: n ± 0.004
Repeatability	± 0.2 Å – Tested on NIST 150 Å SiO <sub>2</sub> /Si

### Facility Requirements

Operating systems	Windows® 2000 / XP / Vista
Power supply	100 V / 115 V / 230 V; 200 W; 50 / 60 Hz
Weight	80 kg
Certificate	CE



Technology Spectroscopic Ellipsometer, liquid crystal modulation based

**HORIBA** JOBIN YVON



# Auto SE

The simple solution  
to measure thin films



Film thickness,  
Optical constants,  
and Imaging

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# Auto SE

“Designed for your thin film measurements,  
to deliver maximum efficiency with simplicity”

The Auto SE is a new thin film measurement tool that allows full automatic analysis of thin film samples with simple push button operation.

Sample analysis takes only a few seconds and provides a complete report that fully describes the thin film stack – including film thicknesses, optical constants, surface roughness, and film inhomogeneities.

The Auto SE includes numerous automatic features, and the patented MyAutoView vision system allows the user to measure at exactly the right place every time.

The Auto SE is a turnkey instrument ideal for routine thin film measurement and device quality control.

## Thin Film Analysis Made Easy

- Ready-to-use system configured to meet your specific application needs
- Full automatic analysis of thin film samples with simple push button operation
- Comprehensive display results with automatic reporting and compliance
- Multilanguage software

“Optimized for enhanced functionality and flexibility”

## MyAutoView Vision System

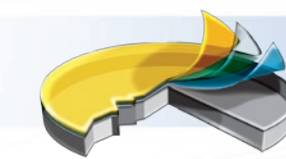
- Visualization of the measurement site for all kinds of sample
- Exact positioning of the measurement spot on a sample
- Unique advantage for measurement of transparent substrates
- Integrated microspot optics

## Highly Featured System

- Automatic sample loading and adjustment
- Automatic sample mapping
- Fast measurement from 440-850 nm < 1s
- Automated selection of eight spot sizes
- Accessories to suit all applications

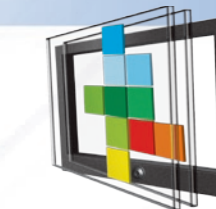
## Intelligent Diagnostics

- Detect and diagnose problems automatically with comprehensive operator guidance for troubleshooting
- Stage with integrated reference samples for instrument quality control
- Simple instrument maintenance



### Functional Coatings

- Optical coatings: Anti reflective, self-cleaning, electrochromic, mirrors
- Surface coatings and treatments: polymers, oil,  $Al_2O_3$



### Flat Panel Displays

- TFT
- OLED
- Plasma display panel
- Flexible display



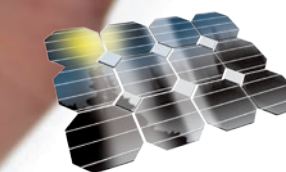
### Biological and Chemical Engineering

- Organic films, LB, SAM, protein
- Film adsorption
- Surface functionalization
- Liquids



### Semiconductors

- Dielectrics
- Thin metal films
- Polymers, photoresists
- Silicon
- PZT
- Laser diodes: GaN, AlGaIn
- Transparent electronics



### Photovoltaic Devices

- Amorphous, poly, micro, nano crystalline silicon
- Transparent conducting oxides
- Anti-reflective coatings
- Organic materials

# Broad Range

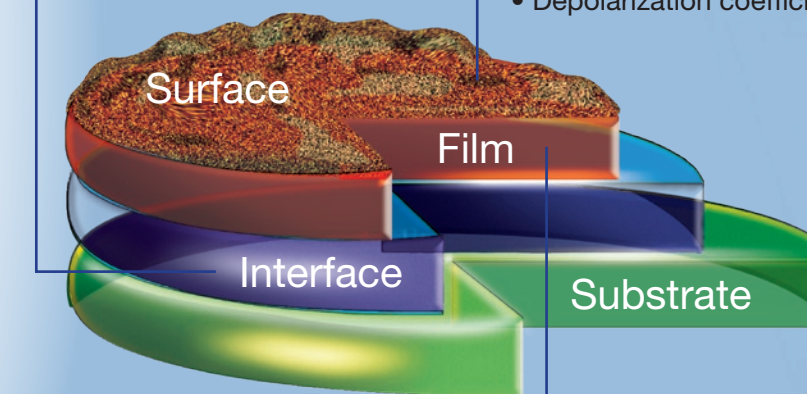
of Thin Film Applications

## Interfacial Behavior

- Interface thickness
- Composition of mixed materials forming interface
- Monitor interface thickness in real-time: film growth, film adsorption
- Monitor real-time changes at interfaces

## Surface Measurement

- Roughness thickness
- Native oxide thickness
- Any surface film thickness
- Depolarization coefficient



## Thickness Measurement

- From a few Å to 15 µm
- Single and multi layers

## Optical Properties

- Optical constants (n,k) and α
- Optical bandgap  $E_g$
- Transmittance

## Material Properties

- Graded and anisotropic film
- Film porosity expressed in void percentage

